

# Cp E 432: Testing of Computing Systems

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for- manufacture, system testability and diagnosability.

## 3 Credits

- Prerequisites
- EI E 351: Electronics Circuits I \$target.descriptions.MinimumGrade\$
- El E 385: Advanced Digital Systems \$target.descriptions.MinimumGrade\$
- <u>EI E 386: Advanced Digital Systems Laboratory</u> \$target.descriptions.MinimumGrade\$

#### Instruction Type(s)

• Lecture: Lecture for Cp E 432

### **Subject Areas**

<u>Computer Engineering, General</u>

#### **Related Areas**

<u>Computer Hardware Engineering</u>

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